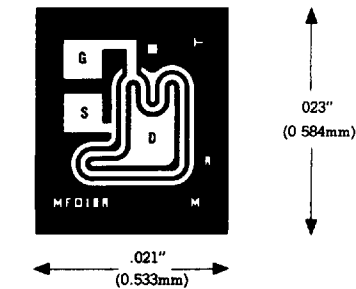


PRODUCT CATALOG

P-CHANNEL ENHANCEMENT MOS FET

CHIP NUMBER

FMP1.1



Die Size: 21 x 23 (mils)
0.533 x 0.584(mm)

Pad Size: 4 x 4 (mils)

BODY-SUBSTRATE

CONTACT METALLIZATION

Top Contact: > 12,000
Å Aluminum

Backside Contact: 3,000 Å Gold

ASSEMBLY RECOMMENDATIONS

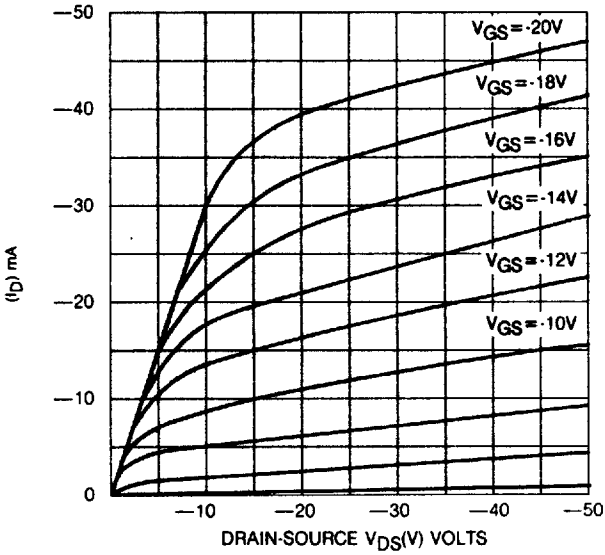
- It is advisable that:
- a) the die be eutectically mounted with gold silicon preform 98/2%.
 - b) 1 mil (0.0254mm) aluminum wire be ultrasonically attached to the top contact.

TYPICAL ELECTRICAL CHARACTERISTICS

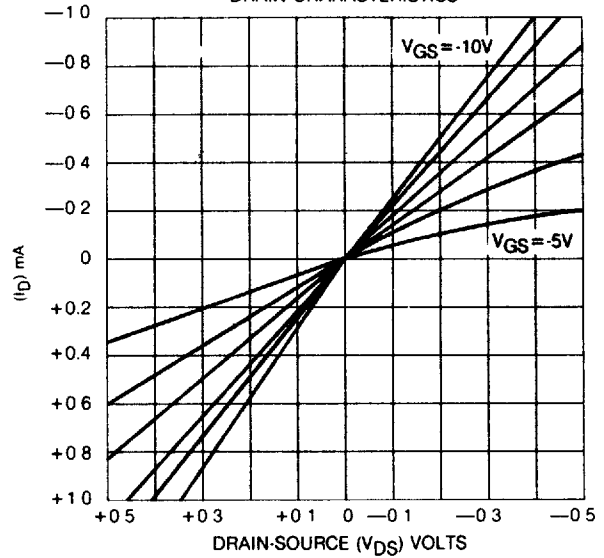
PARAMETER	MIN.	TYP	MAX.	UNIT	TEST CONDITIONS
BVGSS	-35	-40	-60	V	$I_D = 10, \mu A, V_{GS} = 0, V_{BS} = 0$
IDSS		20	500	pA	$V_{DS} = -15V, V_{GS} = 0, V_{BS} = 0$
gfs	1000	2500	4000	μmho	$V_{DS} = -15V, I_D = 10mA, f = 1KHz$
ID(on)	-3.0		-30	mA	$V_{DS} = -15V, V_{GS} = -10V, V_{BS} = 0$
rDS		200	350	Ω	$V_{GS} = -20V, I_D = -100\mu A, V_{BS} = 0$
VGS(th)	-2.0		-5.0	V	$V_{DS} = -15V, I_D = -10\mu A, V_{BS} = 0$
Ciss			1.0	pF	$V_{DS} = -15V, I_D = -10mA, f = 1MHz$
Ciss			3.5	pF	$V_{DS} = -15V, I_D = -10mA, f = 1MHz$
en		50		nV/ $\sqrt{Hz}$	$V_{DS} = -15V, I_D = -10mA, f = 1KHz$

TYPICAL DEVICE TYPES: 2N4065, 3N163, 3N164, UC1700, UC1702

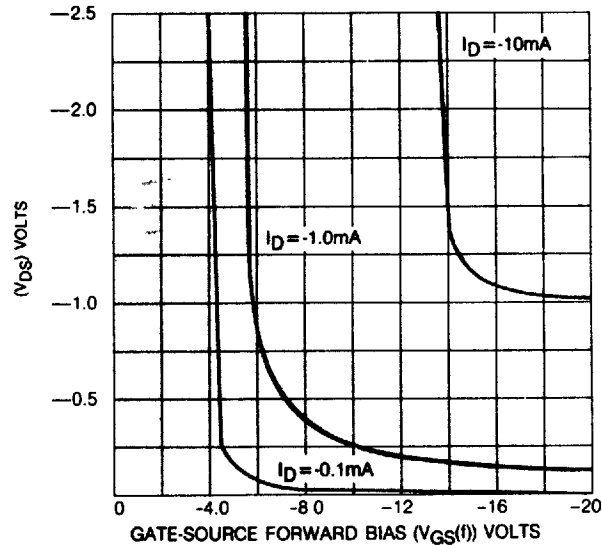
DRAIN CHARACTERISTICS—
COMMON-SOURCE



LOW LEVEL
DRAIN CHARACTERISTICS



LOW-LEVEL "ON" DRAIN SOURCE VOLTAGE
VS GATE-SOURCE FORWARD BIAS VOLTAGE



STATIC DRAIN-SOURCE ON RESISTANCE
VS GATE-SOURCE FORWARD BIAS

